

DUAL FREQUENCY CRYSTAL OSCILLATOR (XO) (10 MHz TO 1.4 GHz)

Features

- Available with any-frequency output frequencies from 10 MHz to 945 MHz and select frequencies to 1.4 GHz
- Two selectable output frequencies
- 3rd generation DSPLL[®] with superior jitter performance
- 3x better frequency stability than SAW-based oscillators
- Internal fixed crystal frequency ensures high reliability and low aging
- Available CMOS, LVPECL, LVDS, and CML outputs
- 3.3, 2.5, and 1.8 V supply options
- Industry-standard 5 x 7 mm package and pinout
- Pb-free/RoHS-compliant

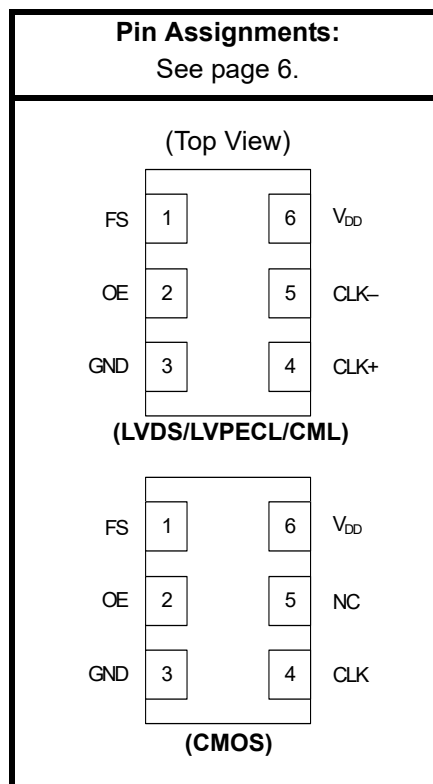
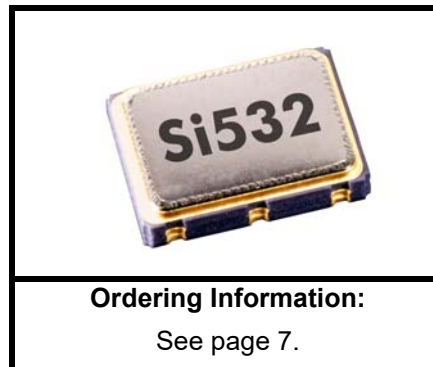
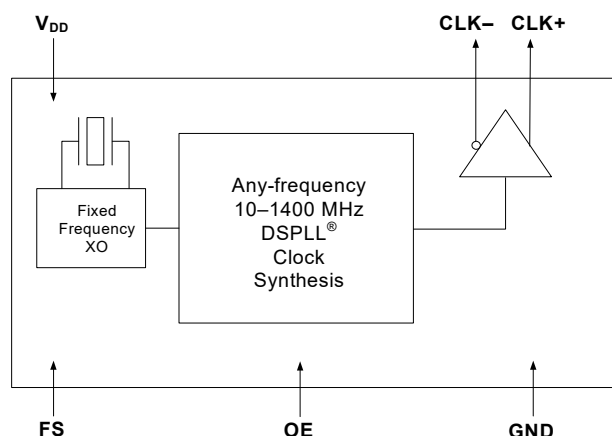
Applications

- SONET/SDH
- Networking
- SD/HD video
- Test and measurement
- Clock and data recovery
- FPGA/ASIC clock generation

Description

The Si532 dual frequency XO utilizes Silicon Laboratories' advanced DSPLL[®] circuitry to provide a low jitter clock at high frequencies. The Si532 is available with any-frequency output frequency from 10 to 945 MHz and select frequencies to 1400 MHz. Unlike a traditional XO where a different crystal is required for each output frequency, the Si532 uses one fixed crystal frequency to provide a wide range of output frequencies. This IC based approach allows the crystal resonator to provide exceptional frequency stability and reliability. In addition, DSPLL clock synthesis provides superior supply noise rejection, simplifying the task of generating low jitter clocks in noisy environments typically found in communication systems. The Si532 IC based XO is factory configurable for a wide variety of user specifications including frequency, supply voltage, output format, and temperature stability. Specific configurations are factory programmed at time of shipment, thereby eliminating long lead times associated with custom oscillators.

Functional Block Diagram



1. Electrical Specifications

Table 1. Recommended Operating Conditions

| Parameter | Symbol | Test Condition | Min | Typ | Max | Units |
|--|-----------------|--------------------------|------------------------|-----|------|-------|
| Supply Voltage ¹ | V _{DD} | 3.3 V option | 2.97 | 3.3 | 3.63 | V |
| | | 2.5 V option | 2.25 | 2.5 | 2.75 | V |
| | | 1.8 V option | 1.71 | 1.8 | 1.89 | V |
| Supply Current | I _{DD} | Output enabled LVPECL | — | 111 | 121 | mA |
| | | CML | — | 99 | 108 | |
| | | LVDS | — | 90 | 98 | |
| | | CMOS | — | 81 | 88 | |
| | | Tristate mode | — | 60 | 75 | mA |
| Output Enable (OE) and Frequency Select (FS) ² | | V _{IH} | 0.75 x V _{DD} | — | — | V |
| | | V _{IL} | — | — | 0.5 | V |
| Operating Temperature Range | T _A | | −40 | — | 85 | °C |

Notes:

- Selectable parameter specified by part number. See Section 3. "Ordering Information" on page 7 for further details.
- OE and FS pins include a 17 kΩ pullup resistor to V_{DD}. Pulling OE to ground causes outputs to tristate.

Table 2. CLK± Output Frequency Characteristics

| Parameter | Symbol | Test Condition | Min | Typ | Max | Units |
|--------------------------------------|----------------|--|-----|------|-------|-------|
| Nominal Frequency ^{1,2} | f _O | LVPECL/LVDS/CML | 10 | — | 945 | MHz |
| | | CMOS | 10 | — | 160 | MHz |
| Initial Accuracy | f _i | Measured at +25 °C at time of shipping | — | ±1.5 | — | ppm |
| Temperature Stability ^{1,3} | | | −7 | — | +7 | ppm |
| | | | −20 | — | +20 | |
| | | | −50 | — | +50 | |
| Aging | f _a | Frequency drift over first year | — | — | ±3 | ppm |
| | | Frequency drift over 20 year life | — | — | ±10 | ppm |
| Total Stability | | Temp stability = ±7 ppm | — | — | ±20 | ppm |
| | | Temp stability = ±20 ppm | — | — | ±31.5 | ppm |
| | | Temp stability = ±50 ppm | — | — | ±61.5 | ppm |

Notes:

- See Section 3. "Ordering Information" on page 7 for further details.
- Specified at time of order by part number. Also available in frequencies from 970 to 1134 MHz and 1213 to 1417 MHz.
- Selectable parameter specified by part number.
- Time from powerup or tristate mode to f_O.

Table 2. CLK± Output Frequency Characteristics (Continued)

| Parameter | Symbol | Test Condition | Min | Typ | Max | Units |
|-------------------------------|------------------|----------------|-----|-----|-----|-------|
| Powerup Time ⁴ | t _{OSC} | | — | — | 10 | ms |
| Settling Time After FS Change | t _{FRQ} | | — | — | 10 | ms |

Notes:

1. See Section 3. "Ordering Information" on page 7 for further details.
2. Specified at time of order by part number. Also available in frequencies from 970 to 1134 MHz and 1213 to 1417 MHz.
3. Selectable parameter specified by part number.
4. Time from powerup or tristate mode to f_O.

Table 3. CLK± Output Levels and Symmetry

| Parameter | Symbol | Test Condition | Min | Typ | Max | Units |
|-----------------------------------|---------------------------------|---|------------------------|------------------------|------------------------|-----------------|
| LVPECL Output Option ¹ | V _O | mid-level | V _{DD} - 1.42 | — | V _{DD} - 1.25 | V |
| | V _{OD} | swing (diff) | 1.1 | — | 1.9 | V _{PP} |
| | V _{SE} | swing (single-ended) | 0.55 | — | 0.95 | V _{PP} |
| LVDS Output Option ² | V _O | mid-level | 1.125 | 1.20 | 1.275 | V |
| | V _{OD} | swing (diff) | 0.5 | 0.7 | 0.9 | V _{PP} |
| CML Output Option ² | V _O | 2.5/3.3 V option mid-level | — | V _{DD} - 1.30 | — | V |
| | | 1.8 V option mid-level | — | V _{DD} - 0.36 | — | V |
| | V _{OD} | 2.5/3.3 V option swing (diff) | 1.10 | 1.50 | 1.90 | V _{PP} |
| | | 1.8 V option swing (diff) | 0.35 | 0.425 | 0.50 | V _{PP} |
| CMOS Output Option ³ | V _{OH} | I _{OH} = 32 mA | 0.8 x V _{DD} | — | V _{DD} | V |
| | V _{OL} | I _{OL} = 32 mA | — | — | 0.4 | |
| Rise/Fall time (20/80%) | t _R , t _F | LVPECL/LVDS/CML | — | — | 350 | ps |
| | | CMOS with C _L = 15 pF | — | 1 | — | ns |
| Symmetry (duty cycle) | SYM | LVPECL: V _{DD} - 1.3 V (diff) LVDS: 1.25 V (diff) CMOS: V _{DD} /2 | 45 | — | 55 | % |

Notes:

1. 50 Ω to V_{DD} - 2.0 V.
2. R_{term} = 100 Ω (differential).
3. C_L = 15 pF

Table 4. CLK± Output Phase Jitter

| Parameter | Symbol | Test Condition | Min | Typ | Max | Units |
|--|----------------|--|-----|------|------|-------|
| Phase Jitter (RMS) ¹ for F _{OUT} ≥ 500 MHz | ϕ _J | 12 kHz to 20 MHz (OC-48) | — | 0.25 | 0.40 | ps |
| | | 50 kHz to 80 MHz (OC-192) | — | 0.26 | 0.37 | ps |
| Phase Jitter (RMS) ¹ for F _{OUT} of 125 to 500 MHz | ϕ _J | 12 kHz to 20 MHz (OC-48) | — | 0.36 | 0.50 | ps |
| | | 50 kHz to 80 MHz (OC-192) ² | — | 0.34 | 0.42 | ps |
| Phase Jitter (RMS) ¹ for F _{OUT} of 125 and 156.25 MHz Only | ϕ _J | 12 kHz to 20 MHz (Brickwall) | — | 0.25 | 0.40 | ps |
| Phase Jitter (RMS) for F _{OUT} of 10 to 160 MHz CMOS Output Only | ϕ _J | 12 kHz to 20 MHz (OC-48) ² | — | 0.62 | — | ps |
| | | 50 kHz to 20 MHz ² | — | 0.61 | — | ps |

Notes:

1. Refer to AN256 for further information.
2. Max offset frequencies: 80 MHz for F_{OUT} ≥ 250 MHz, 20 MHz for 50 MHz ≤ F_{OUT} < 250 MHz, 2 MHz for 10 MHz ≤ F_{OUT} < 50 MHz.

Table 5. CLK± Output Period Jitter

| Parameter | Symbol | Test Condition | Min | Typ | Max | Units |
|----------------|------------------|----------------|-----|-----|-----|-------|
| Period Jitter* | J _{PER} | RMS | — | 2 | — | ps |
| | | Peak-to-Peak | — | 14 | — | ps |

***Note:** Any output mode, including CMOS, LVPECL, LVDS, CML. N = 1000 cycles. Refer to AN279 for further information.

Table 6. CLK± Output Phase Noise (Typical)

| Offset Frequency (f) | 120.00 MHz | 156.25 MHz | 622.08 MHz | Units |
|----------------------|------------|------------|------------|--------|
| | LVDS | LVPECL | LVPECL | |
| 100 Hz | -112 | -105 | -97 | dBc/Hz |
| 1 kHz | -122 | -122 | -107 | |
| 10 kHz | -132 | -128 | -116 | |
| 100 kHz | -137 | -135 | -121 | |
| 1 MHz | -144 | -144 | -134 | |
| 10 MHz | -150 | -147 | -146 | |
| 100 MHz | n/a | n/a | -148 | |

Table 7. Environmental Compliance

The Si532 meets the following qualification test requirements.

| Parameter | Conditions/Test Method |
|----------------------------|--------------------------|
| Mechanical Shock | MIL-STD-883, Method 2002 |
| Mechanical Vibration | MIL-STD-883, Method 2007 |
| Solderability | MIL-STD-883, Method 2003 |
| Gross & Fine Leak | MIL-STD-883, Method 1014 |
| Resistance to Solder Heat | MIL-STD-883, Method 2036 |
| Moisture Sensitivity Level | J-STD_020, MSL1 |
| Contact Pads | Gold over Nickel |

Table 8. Thermal Characteristics

(Typical values $T_A = 25\text{ }^\circ\text{C}$, $V_{DD} = 3.3\text{ V}$)

| Parameter | Symbol | Test Condition | Min | Typ | Max | Unit |
|--|---------------|----------------|-----|------|-----|--------------------|
| Thermal Resistance Junction to Ambient | θ_{JA} | Still Air | — | 84.6 | — | $^\circ\text{C/W}$ |
| Thermal Resistance Junction to Case | θ_{JC} | Still Air | — | 38.8 | — | $^\circ\text{C/W}$ |
| Ambient Temperature | T_A | | -40 | — | 85 | $^\circ\text{C}$ |
| Junction Temperature | T_J | | — | — | 125 | $^\circ\text{C}$ |

Table 9. Absolute Maximum Ratings¹

| Parameter | Symbol | Rating | Units |
|--|------------|------------------------|------------------|
| Maximum Operating Temperature | T_{AMAX} | 85 | $^\circ\text{C}$ |
| Supply Voltage, 1.8 V Option | V_{DD} | -0.5 to +1.9 | V |
| Supply Voltage, 2.5/3.3 V Option | V_{DD} | -0.5 to +3.8 | V |
| Input Voltage (any input pin) | V_I | -0.5 to $V_{DD} + 0.3$ | V |
| Storage Temperature | T_S | -55 to +125 | $^\circ\text{C}$ |
| ESD Sensitivity (HBM, per JESD22-A114) | ESD | 2500 | V |
| Soldering Temperature (Pb-free profile) ² | T_{PEAK} | 260 | $^\circ\text{C}$ |
| Soldering Temperature Time @ T_{PEAK} (Pb-free profile) ² | t_P | 20–40 | seconds |

Notes:

1. Stresses beyond those listed in Absolute Maximum Ratings may cause permanent damage to the device. Functional operation or specification compliance is not implied at these conditions.
2. The device is compliant with JEDEC J-STD-020C. Refer to Si5xx Packaging FAQ available for download at www.silabs.com/VCXO for further information, including soldering profiles.

2. Pin Descriptions

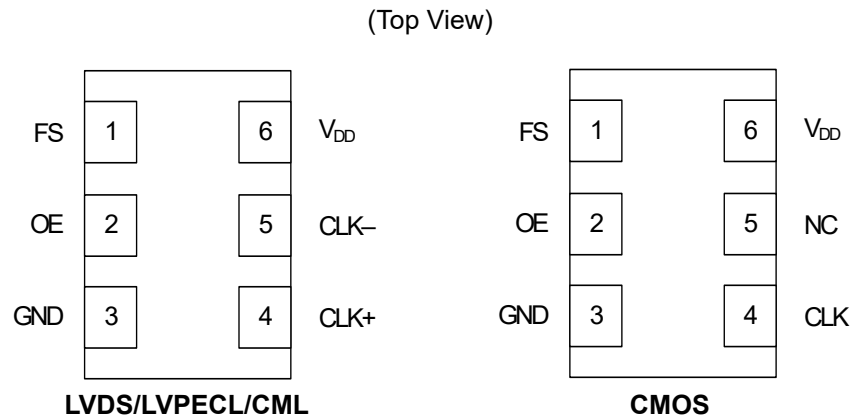


Table 10. Pin Descriptions

| Pin | Symbol | LVDS/LVPECL/CML Function | CMOS Function |
|-----|-----------------|--|--|
| 1 | FS* | Frequency Select 0 = First frequency selected 1 = Second frequency selected | Frequency Select 0 = First frequency selected 1 = Second frequency selected |
| 2 | OE* | Output enable 0 = clock output disabled (outputs tristated) 1 = clock output enabled | Output enable 0 = clock output disabled (outputs tristated) 1 = clock output enabled |
| 3 | GND | Electrical and Case Ground | Electrical and Case Ground |
| 4 | CLK+ | Oscillator Output | Oscillator Output |
| 5 | CLK- | Complementary Output | No connection |
| 6 | V _{DD} | Power Supply Voltage | Power Supply Voltage |

***Note:** FS and OE include a 17 kΩ pullup resistor to V_{DD}. See Section 3. “Ordering Information” for details on frequency value ordering.

3. Ordering Information

The Si532 XO supports a variety of options including frequency, temperature stability, output format, and V_{DD} . Specific device configurations are programmed into the Si532 at time of shipment. Configurations can be specified using the Part Number Configuration chart below. Silicon Laboratories provides a web browser-based part number configuration utility to simplify this process. Refer to www.silabs.com/VCXOPartNumber to access this tool and for further ordering instructions. The Si532 is supplied in an industry-standard, RoHS-compliant, 6-pad, 5 x 7 mm package.

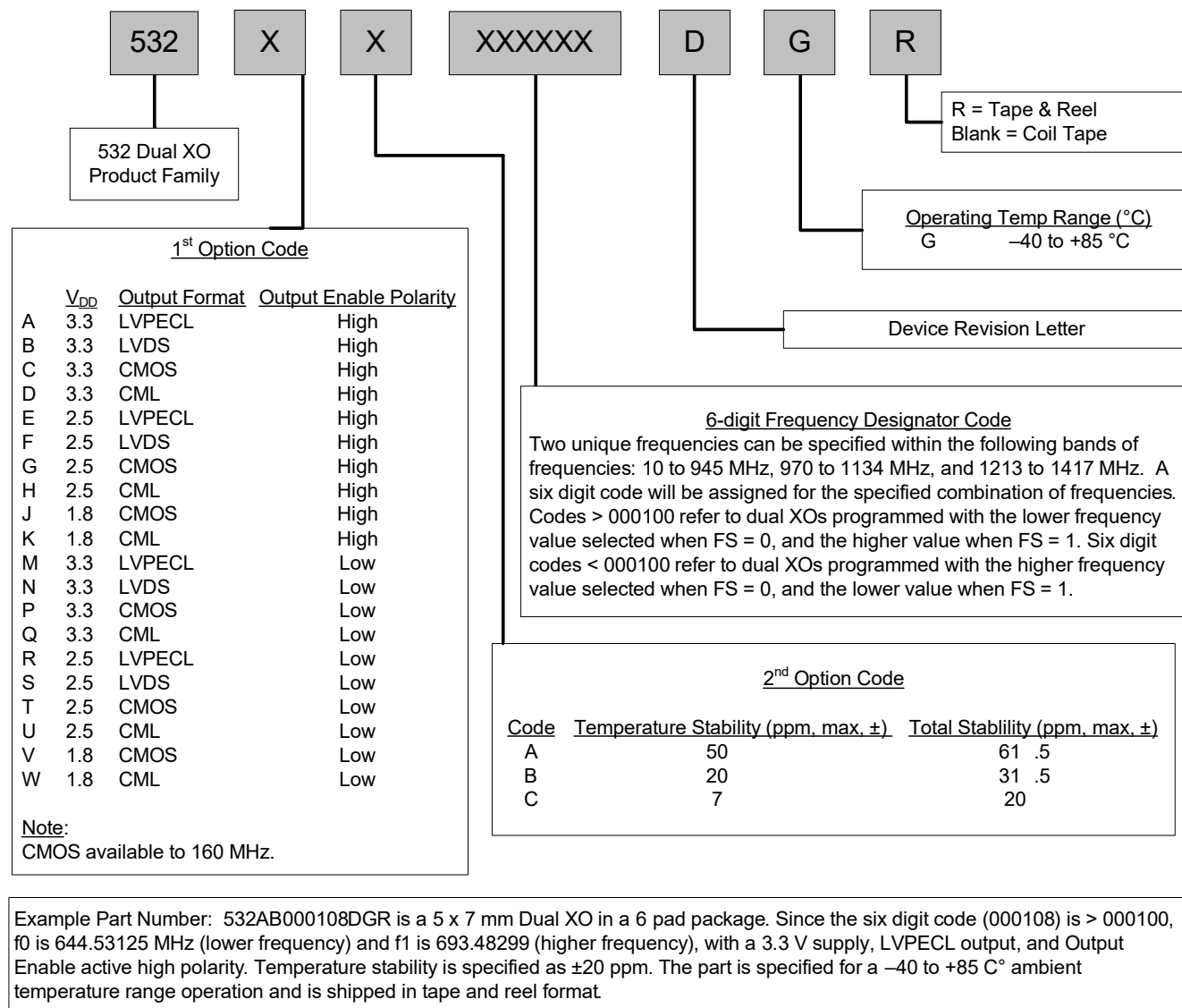


Figure 1. Part Number Convention

4. Outline Diagram and Suggested Pad Layout

Figure 2 illustrates the package details for the Si532. Table 11 lists the values for the dimensions shown in the illustration.

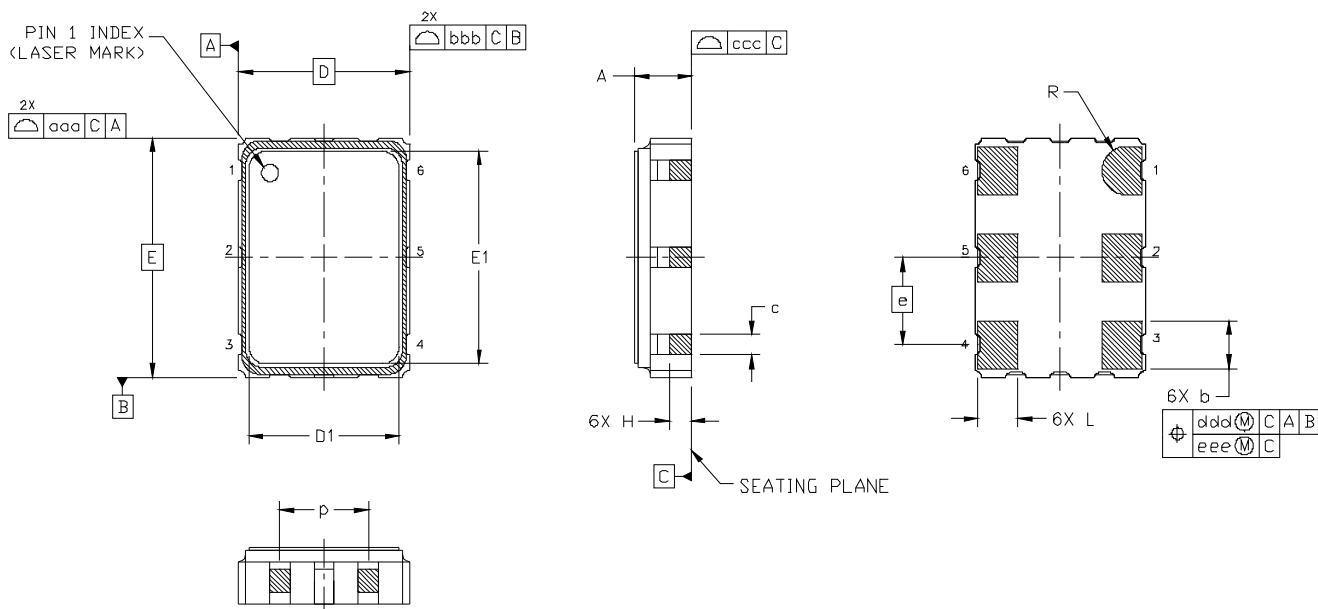


Figure 2. Si532 Outline Diagram

Table 11. Package Diagram Dimensions (mm)

| Dimension | Min | Nom | Max |
|-----------|----------|------|------|
| A | 1.50 | 1.65 | 1.80 |
| b | 1.30 | 1.40 | 1.50 |
| c | 0.50 | 0.60 | 0.70 |
| D | 5.00 BSC | | |
| D1 | 4.30 | 4.40 | 4.50 |
| e | 2.54 BSC | | |
| E | 7.00 BSC | | |
| E1 | 6.10 | 6.20 | 6.30 |
| H | 0.55 | 0.65 | 0.75 |
| L | 1.17 | 1.27 | 1.37 |
| p | 1.80 | — | 2.60 |
| R | 0.70 REF | | |
| aaa | 0.15 | | |
| bbb | 0.15 | | |
| ccc | 0.10 | | |
| ddd | 0.10 | | |
| eee | 0.05 | | |

5. Si532 Mark Specification

Figure 3 illustrates the mark specification for the Si532. Table 12 lists the line information.

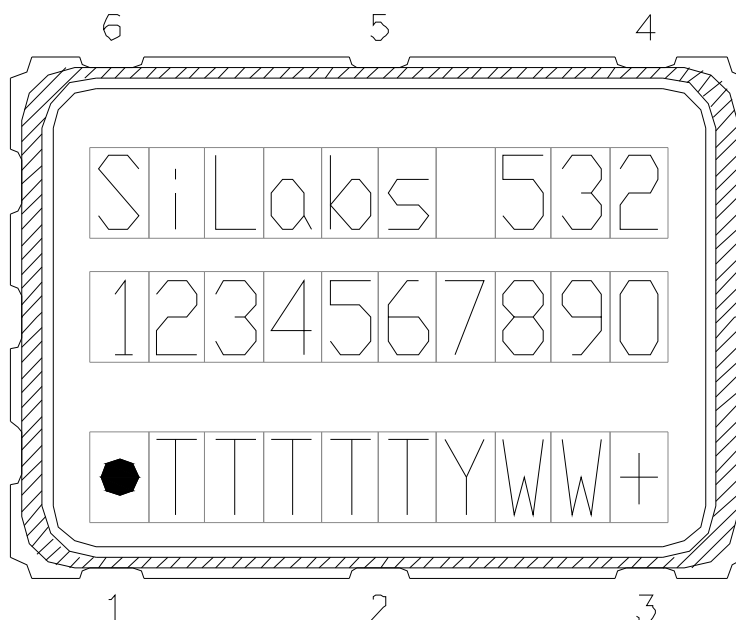


Figure 3. Mark Specification

Table 12. Si53x Top Mark Description

| Line | Position | Description |
|------|-------------------|---|
| 1 | 1–10 | “SiLabs 532” |
| 2 | 1–10 | Si532: Option1 + Option2 + ConfigNum(6) + Temp |
| 3 | Trace Code | |
| | Position 1 | Pin 1 orientation mark (dot) |
| | Position 2 | Product Revision (D) |
| | Position 3–6 | Tiny Trace Code (4 alphanumeric characters per assembly release instructions) |
| | Position 7 | Year (least significant year digit), to be assigned by assembly site (ex: 2007 = 7) |
| | Position 8–9 | Calendar Work Week number (1–53), to be assigned by assembly site |
| | Position 10 | “+” to indicate Pb-Free and RoHS-compliant |

DOCUMENT CHANGE LIST

Revision 1.0 to Revision 1.1

- Updated Table 1, “Recommended Operating Conditions,” on page 2.
 - Device maintains stable operation over –40 to +85 °C operating temperature range.
 - Supply current specifications updated for revision D.
- Updated Table 2, “CLK± Output Frequency Characteristics,” on page 2.
 - Added specification for ±20 ppm lifetime stability (±7 ppm temperature stability) XO.
- Updated Table 3, “CLK± Output Levels and Symmetry,” on page 3.
 - Updated LVDS differential peak-peak swing specifications.
- Updated Table 4, “CLK± Output Phase Jitter,” on page 4.
- Updated Table 5, “CLK± Output Period Jitter,” on page 4.
 - Revised period jitter specifications.
- Updated Table 9, “Absolute Maximum Ratings¹,” on page 5 to reflect the soldering temperature time at 260 °C is 20–40 sec per JEDEC J-STD-020C.
- Updated 3. “Ordering Information” on page 7.
 - Changed ordering instructions to revision D.
- Added 5. “Si532 Mark Specification” on page 9.

Revision 1.1 to Revision 1.2

- Updated 2.5 V/3.3 V and 1.8 V CML output level specifications for Table 3 on page 3.
- Added footnotes clarifying max offset frequency test conditions for Table 4 on page 4.
- Removed the words “Differential Modes: LVPECL/LVDS/CML” in the footnote referring to AN256 in Table 4 on page 4.
- Added CMOS phase jitter specs to Table 4 on page 4.
- Updated Table 7 on page 5 to include the “Moisture Sensitivity Level” and “Contact Pads” rows.
- Revised Figure 2 on page 8 to reflect current package outline diagram.
- Updated Figure 3 and Table 12 on page 9 to reflect specific marking information. Previously, Figure 3 was generic.

Revision 1.2 to Revision 1.3

- Added Table 8, “Thermal Characteristics,” on page 5.

Revision 1.3 to Revision 1.31

May 2, 2016

- Updated Table 4 to include 125 MHz and 156.25 MHz jitter measurements.

Revision 1.31 to Revision 1.4

June, 2018

- Changed “Trays” to “Coil Tape” in section 3. “Ordering Information”.



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